## Notice of References Cited Application/Control No. 10/649,681 Examiner John E Chapman Applicant(s)/Patent Under Reexamination OGAWA, EIJI Page 1 of 1

## **U.S. PATENT DOCUMENTS**

	U.S. FAILIT DOCUMENTS									
*	·	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification					
	A	US-6,066,099	05-2000	Thomenius et al.	600/447					
	В	US-								
	С	US-								
	D	US-								
	E	US-								
	F	US-								
	G	US-								
	Н	US-								
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## FOREIGN PATENT DOCUMENTS

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## **NON-PATENT DOCUMENTS**

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